Stage Micrometers

For Stereo and Compound Microscopes, Metallographs, Video and Automatic Measuring Systems

Stage Micrometers are microscopic rules used as length standards when calibrating or verifying Image Analyzers, Automatic Micro/Macro Hardness Testers, Video Measuring Systems, Video Prints, or Measuring Reticles.

Dual Use

Suitable for use with low AND high magnification systems. Calibrated at 0.010 mm (10 μ m), 0.10 mm, 0.001 inch, and 0.01 inch increments. Appears as black lines on a white background in reflected light, and white lines on a dark background in transmitted light. Glass insert in a 1" X 3" metal slide for durability.

Reference LECO Stage Micrometer Part Number 863-783-146 Traceable LECO Stage Micrometer Part Number 863-783-146CERT

High Magnification Applications

A 1 mm full scale optimized for reflected light. Each increment is 0.010 mm (10 μ m). Appears as black lines on a white background. Glass insert in a 1" x 3" metal slide for durability.

Reference 1 mm Stage Micrometer Part Number 860-256 Traceable 1 mm Stage Micrometer Part Number 860-256-110

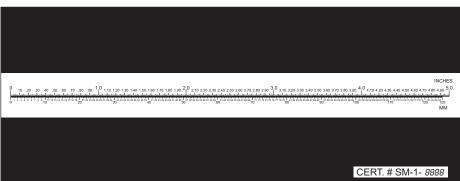
English and Metric scales in a crosshair configuration optimized for transmitted light. White lines on a darker background. Minimum English increment is 0.0005 inch. Minimum Metric increment is 0.010 mm (10 μ m). 1" x 3" glass slide.

Reference Crosshair Stage Micrometer Part Number 861-377

Low Magnification (Macro) Applications

English and Metric scales. English scale is 5 inches long with graduations at each 0.010 inch. Metric scale is 125 mm long with graduations at each 0.10 mm. 2" x 6" glass plate.

Reference Macro Stage Micrometer Part Number 861-249-101 Traceable Macro Stage Micrometer Part Number 861-375-110





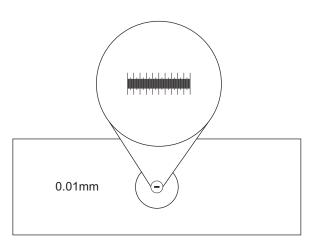
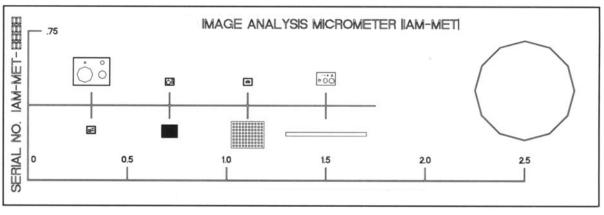


Image Analysis Standard 861-249-107

Test Plate	Frame True Size	Description
1	4600 x 3500 μm	CIRCLES with diameters of 2000, 1000, 500, 250 $\mu{ m m}$; available for secondary certification on special request; Reference
2	1000 x 800 μ m	CIRCLES with diameters of 500, 250, 125, 62.5 μ m; available for secondary certification on special request; Reference
3	1000 x 800 μm	BARS of 200 x 20 $\mu{ m m}$ with 30 degree angles; Reference
4	2400 x 1620 μm	RANDOM SHAPES: approximately 5, 15, 35, 75, 150, 250, 300, 600, 675 μ m high; Reference
Test Plate		
icor ridic	Frame True Size	Description
5	Frame True Size 4000 x 3200 μm	Description SQUARES of sizes of 100, 40, 20 μm (two sets); Reference
		•
5	4000 x 3200 μm	SQUARES of sizes of 100, 40, 20 μ m (two sets); Reference
5 6	4000 x 3200 μm 2050 x 1650 μm	SQUARES of sizes of 100, 40, 20 μm (two sets); Reference GRID Pattern with 50 μm holesand walls; Reference

Grain Size/Nodularity Standard

TEST PLATE #4 has nine randomly generated shapes to stimulate granular features ideally suited for metallurgical calibration where dimensional shapes to be measured with accuracy (see Figure 1 below).





Traceable – Provided with accredited calibration certificate(s) containing actual measurements for the nominal division markings. Uncertainties are included for each value reported. For routine calibration of critical measurement systems of users subject to audit, or requiring the utmost in accuracy.

Reference – No documentation provided. For routine calibration and verification of non-critical measurement systems.

Specifications and part numbers may change. Consult LECO for latest information.

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